How to Faster Test a Device for Different Combinations of Parameters

Francisco Zapata[1] and Luis Gutierrez[2]

[1]Department of Industrial and Systems Engineering and
[2]Department of Computer Science
University of Texas at El Paso
El Paso, TX 79968, USA
fazg74@gmail.com, lcgutierrez@miners.utep.edu

Abstract. A device has to function properly under all possible conditions: e.g., for all temperatures within a given range, for all possible humidity values within a given range, etc. Ideally, it would be nice to be able to test a device for all possible combinations of these parameters, but the number of such combinations is often so huge that such an exhaustive testing is not possible. Instead, it is reasonable to check the device for all possible values of each parameter, for each possible pairs of values of two parameters, and, in general, for all possible combinations of values of k parameters for some k. For n parameters, a straightforward testing design with this property contains $O(n^k)\cdot N^k$ experiments, where N is the number of tested values of each parameter. We show that, by using a more sophisticated testing design, we can decrease the number of experiments to a much smaller number $O(\log^{k-1}(n))\cdot N^k$.

1 Formulation of the Problem

It is important to test a device for different combinations of parameters. Many devices have to function correctly under many different values of the corresponding parameters: e.g., for temperatures within the given range, for pressure within the given range, for humidity within the given range, etc.

It is not possible to test all possible combinations of parameters. Ideally, we should test the device for all possible combinations of the corresponding parameters. However, often, such a testing is not realistic. For example, if we have 20 possible parameters, and we consider 10 possible values of each of these parameters, then testing all possible combinations would require an unrealistic amount of 10^{20} tests. Even in the idealized situation when each test takes 1 second, then, with $3\cdot 10^7$ seconds in a year, this testing would require $3\cdot 10^{12}$ years – longer than the lifetime of the Universe.

Solution: test for all pairs, or all triples, etc. Since we cannot test for all possible combinations of all the parameters, we need to test at least for all possible values of each parameter separately. In other words, we need to test the device for all possible values of outside temperature, then test this device for all possible values of humidity, etc.

In this testing, we may overlook possible joint effect of two or more different parameters. To take such an effect into account, it makes sense to arrange the tests in such a way that for every two parameters, we test all possible combinations of values. Similarly, we may want to test in such a way that for every three parameters, we test all possible combinations of values, etc.; see, e.g., [1–4].

How to arrange such a test: first simple idea. For each parameter x_i, we have a range $[\underline{x}_i, \overline{x}_i]$ of possible values. Let us assume that for each parameter, we test for N different values $x_{i1} < x_{i2} < \ldots < x_{iN}$. In this case, we need N experiments to test the device's behavior for all N values of each parameter.

If we simply want to test for all possible values of each parameter, then a straightforward idea is to first test all possible values of the first parameter x_1, then test all possible values of the second parameter x_2, etc., until we have tested all the parameters. If we denote by n the number of parameters, then this scheme requires $n \cdot N$ experiments.

If we want to test all possible pairs of parameters, then, for each of $\binom{n}{2}$ pairs of parameters, we test all possible N^2 pairs of values. This requires $\binom{n}{2} \cdot N^2$ experiments.

Similarly, if we want to test all possible triples of parameters, then for each of $\binom{n}{3}$ triples of parameters, we test all possible N^3 triples of values. This requires $\binom{n}{3} \cdot N^3$ experiments. In general, if we fix an integer k, and we want to test all possible combinations of values of each k parameters, then for each of $\binom{n}{k}$ k-tuples of parameters, we test all possible N^k combinations of values. This requires $\binom{n}{k} \cdot N^k$ experiments.

We can test faster than that. It is easy to see that the simple straightforward approach uses too many combinations of parameters, we can often use much fewer experiments.

For example, if we want to test all possible values of each parameter, then in the above straightforward approach, we perform $n \cdot N$ experiments. In reality, it is sufficient to perform only N experiments. Namely, in each experiment $j = 1, \ldots, N$, we take each parameter x_i to be equal to x_{ij}:

- in the first experiment, we select the first value of each of n parameters, i.e., use parameters $(x_{11}, \ldots, x_{n1})$;
- in the second experiment, we select the second value of each of n parameters, i.e., use parameters $(x_{12}, \ldots, x_{n2})$;
- $\ldots$

- in the j-th experiment, we select the j-th value of each of n parameters, i.e., use parameters $(x_{1j}, \ldots, x_{nj})$;
- ...
- finally, in the last (N-th) experiment, we select the N-th value of each of n parameters, i.e., use parameters $(x_{1N}, \ldots, x_{nN})$.

When we have many parameters $n \gg 1$, we then have $n \cdot N \gg N$, so this idea drastically decreases the number of necessary experiments – and thus, the testing time.

Comment. In some cases, we have different number of values N_i for different parameters x_i. In this case, in the straightforward approach, we need $\prod\limits_{i=1}^{n} N_i$ combinations, but instead, we can simply use $N = \max(N_i)$ combinations: namely, we set $x_{ij} = x_{iN_i}$ when $j > N_i$. Thus, when all the values N_i are of the same order, we still get a drastic decrease in the number of experiments.

What we do in this paper. In this paper, we show that similar faster testing is possible when we test all possible pairs of parameters, all possible triples, etc.

2 New Testing Design: Main Idea and Step-by-Step Description

Let us formulate the problem in precise terms. The above description leads to the following definition.

Definition. *Let $n > 0$, $N > 0$, and $k > 0$ be positive natural numbers. The number n will be called the* number of parameters*, and the number N will be called the* number of values.

- *By an* experiment*, we mean a tuple of n integers $j_1, \ldots, j_n$, where $1 \le j_i \le N$ for all i. We say that in this experiment, we use the j_i-th value of the i-th parameter. An experiment will also be denoted by $(x_{1i_1}, \ldots, x_{nj_n})$.*
- *By a* testing design*, we mean a finite set of experiments.*
- *We say that a testing design* tests each combination of k parameters *if for every k-tuple $1 \le i_1 < \ldots < i_k \le N$ and for all k-tuples of integers $v_1, \ldots, v_k$, with $1 \le v_\ell \le N$, this testing design contains an experiment in which, for all ℓ from 1 to k, we use the v_ℓ-th value of the i_ℓ-th parameter.*

Main objective. Our main objective is minimize the required number of experiments.

The straightforward ideas leads to a design that tests each combination of k parameters and that consists of $\binom{n}{k} \cdot N^k$ experiments. As a function of the number n of parameters, this number of experiments is $O(n^k) \cdot N^k$.

For $n = k$, we need to test all N^k possible combinations of parameters, so we cannot have fewer than N^k test anyway. However, as the above case of $k = 1$ shows, we can try to minimize the factor depending on n.

Main Result. *For each k, there exists a testing design that tests each combination of k parameters and that consists of $O(\log^{k-1}(n)) \cdot N^k$ experiments.*

Discussion.

- For $k = 1$, we get the known fact that we need $O(N)$ experiments.
- For testing all possible pairs ($k = 2$), we need $O(\log(n)) \cdot N^2$ experiments. This is much smaller than $O(n^2) \cdot N^2$ experiments needed in the straightforward approach.
- For testing all possible triples ($k = 3$), we need $O(\log^2(n)) \cdot N^3$ experiments. This is much smaller than $O(n^3) \cdot N^3$ experiments needed in the straightforward approach.

Description of the new testing design: case of $k = 2$. Let $B = \lceil \log_2(n) \rceil \sim \log(n)$ be the number of bits needed to describe all the natural numbers from 0 to $n-1$. Let us enumerate the bit from lowest to the highest. Let us denote the b-th bit in the binary expansion of an integer i by $\text{bit}_b(i)$. For example, for the binary number $i = 1011_2 = 11_{10}$:

- the first (lowest) bit is 1: $\text{bit}_1(i) = 1$;
- the second bit is 1: $\text{bit}_2(i) = 1$;
- the third bit is 0: $\text{bit}_3(i) = 0$;
- the fourth bit is 1: $\text{bit}_4(i) = 1$, and
- all the other bits are 0s: $\text{bit}_b(i) = 0$ for all $b > 4$.

Our new testing design consists of B groups of experiments. Each of these groups consists of N^2 experiments, so that total number of experiments is indeed $O(\log(n)) \cdot N^2$. In the b-th group of experiments, for each pair of integers (f, s), $1 \le f \le N$ and $1 \le s \le n$:

- we set $j_i = f$ if $\text{bit}_b(i-1) = 0$, and
- we set $j_i = s$ if $\text{bit}_b(i-1) = 1$.

If we have two different integers $i_1 < i_2$, then $i_1 - 1 \ne i_2 - 1$, so at least one bit b in the binary expansions of $i_1 - 1$ and $i_2 - 1$ is different. Thus, for this bit b, the corresponding group of experiments tests all possible pairs (f, s).

Example: $n = 4$. For $n = 4$, we need $B = 2$ bits to represent integers 0, 1, 2, and 3. Here, $0_{10} = 00_2$, $1_{10} = 01_2$, $2_{10} = 10_2$, and $3_{10} = 11_2$. Thus, in this case, we have two groups of N^2 experiments each:

- In the first group of experiments, we assign s to all the values i for which $\text{bit}_1(i-1) = 0$, and f to all the values i for which $\text{bit}_1(i-1) = 1$. Thus, each experiment has the form (f, s, f, s).
- In the second group of experiments, we assign s to all the values i for which $\text{bit}_2(i-1) = 0$, and f to all the values i for which $\text{bit}_2(i-1) = 1$. Thus, each experiment has the form (f, f, s, s).

If $i_1 < i_2$ are both odd or both even, then the second group of experiments tests all possible combinations of the values of the corresponding parameters. If one of the values i_1 and i_2 is odd and another value is even, then the first group of experiments tests all possible combinations of values.

Description of the new testing design: case of $k > 2$. To describe the testing design for $k > 2$, we use the following recursive algorithm that reduces a testing design for given k and n to a testing designs for smaller k and n.

For $n = k$, we just have to test all N^k possible combinations of values of all k parameters.

For $n > k$, we divide the set of n parameters into two halves of size $n/2$. Then:

- To cover situations when all k parameters are in the first half and situations when all k parameters are in the second half, we use the testing design for $n/2$ and k; each experiment in this design is copied for the second half, so, e.g., a design fs becomes $fsfs$ (see example below).
- To cover situations in which $k-1$ parameters are in the first half and 1 parameter is in the second half, we combine each experiment from testing plan for $n/2$ and $k-1$ with each experiment from the testing plan for $n/2$ and 1.
- To cover situations in which $k-2$ parameters are in the first half and 2 parameters are in the second half, we combine each experiment from testing plan for $n/2$ and $k-2$ with each experiment from the testing plan for $n/2$ and 2.
- ...
- To cover situations in which $k-i$ parameters are in the first half and i parameters are in the second half, we combine each experiment from testing plan for $n/2$ and $k-i$ with each experiment from the testing plan for $n/2$ and i.
- ...
- Finally, to cover situations in which 1 parameter are in the first half and $k-1$ parameters are in the second half, we combine each experiment from testing plan for $n/2$ and $k-1$ with each experiment from the testing plan for $n/2$ and 1.

References

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